

INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)	Docket Number (Optional) <b>TWI-11720</b>	Application Number <b>NEW</b>
	Applicant(s) <b>Louis N. Koppel et al.</b>	
	Filing Date <b>HEREWITH</b>	Group Art Unit <b>Unknown</b>

### U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
HK	*AA	5,042,951	08/27/1991	Gold et al.	356	369	09/19/1989
HK	*AB	5,412,473	05/02/1995	Rosencwaig et al.	356	351	07/16/1993
HK	*AC	5,475,728	12/12/1995	Smith et al.	378	81	08/02/1993
HK	*AD	5,619,548	04/08/1997	Koppel	378	70	08/11/1995
HK	*AE	5,878,106	03/02/1999	Fujiwara	378	79	05/29-96
HK	*AF	5,923,720	07/13/1999	Barton et al.	378	84	06/17/1997
HK	*AG	6,041,098	03/21/2000	Touryanski et al.	378	70	02/02/1998
HK	*AH	6,069,934	05/30/2000	Verman et al.	378	73	04/07/1998
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### FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
HK	*AI	144 956	11/12/1980	Germany	G01B	15/02		X
HK	*AJ	WO 92/08104	05/14/1992	PCT	G01B	11/24		
HK	*AK	20011116705	04/27/2001	Japan	G01N	23/207	Abstract	
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### OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

HK	*AL	K. Sakurai et al., "Fourier Analysis of Interference Structure in X-Ray Specular Reflection from Thin Films," <i>Jpn. J. Appl. Phys.</i> , Vol. 31, 1992, pp. L113-L115.						
HK	*AM	K.N. Stoev et al., "Review on grazing incidence X-ray spectrometry and reflectometry," <i>Spectrochimica Acta Part B</i> , Vol. 54, 1999, pp. 41-82.						
HK	*AN	N. Wainfan et al., "Density Measurements of Some Thin Copper Films," <i>Journal of Applied Physics</i> , Vol. 30, No. 10, October 1959, pp. 1604-1609.						
HK	*AO	J.P. Sauro et al., "Some Observations on the Interference Fringes Formed by X Rays Scattered from Thin Films," <i>Physical Review</i> , Vol. 143, No. 1, March 1966, pp. 439-443.						
HK	*AP	K. Sakurai et al., "Analysis of thin films by X-ray scattering at grazing incidence," <i>SPRING-8 User Experiment Report No. 2 (1998 A)</i> , March 1999, p. 162.						

Examiner		Date Considered	<b>05/03/2004</b>
Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.			